SHORT COMMUNICATIONS

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Refinement of the crystal structure of TiSi₂ and some comments on bonding in TiSi₂ and related compounds. By W. JEITSCHKO,* Central Research and Development Department,† Experimental Station, E. I. du Pont de Nemours and Company, Wilmington, DE 19898, USA

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The structure of TiSi₂ was refined from counter data to R = 0.035 for 217 independent structure factors. Lattice constants are a = 8.2671 (9), b = 4.8000 (5), c = 8.5505 (11) Å. None of the interatomic distances differ by more than 0.05 Å from the values of the determination by Laves & Wallbaum [Z. Kristallogr. (1939), 101, 78–93]. A rigid band model accounts well for the electrical properties of the TiSi₂- and CrSi₂-type compounds and for the valence-electron rules governing the defect-TiSi₂ related structures.

The structure of TiSi, (Laves & Wallbaum, 1939) consists of close-packed hexagonal layers of composition TiSi,, stacked on top of each other in such a way that Ti atoms of adjacent layers avoid close contact. Four such layers form a translation period (stacking sequence ABCD). In the CrSi₂and MoSi₂-type structures, which are built up in a similar way, three or two layers, respectively, complete a translation period (stacking sequences ABC and AB). The occurrence of these three structure types is governed by valence-electron rules (Nowotny, 1963). Similar rules (Jeitschko & Parthé, 1967) were also found for the extended series of defect-TiSi, related structures (Nowotny, 1970), the first member of which, Mn₁₁Si₁₉, was described by Schwomma, Preisinger, Nowotny & Wittmann (1964). Because of the importance of the TiSi, structure for the understanding of these phases we refined it from single-crystal counter data.

A sample of TiSi₂ was prepared from the elemental components (purity >99.9%) by arc melting and subsequent rapid cooling. Single crystals, isolated from the crushed sample, were examined with Mo Ka radiation in a precession camera. They showed the extinctions typical for space group *Fddd* plus the extinctions of the special point positions of the TiSi₂-type structure. Lattice constants were refined from Guinier-Hägg data with high-purity KCl (a = 6.2931 Å) as standard: a = 8.2671 (9), b = 4.8000 (5), c = 8.5505 (11) Å.

A small irregular crystal (50 × 70 × 80 μ m) was used for collecting the intensities on a four-circle diffractometer (Zrfiltered Mo radiation, θ -2 θ scans up to $2\theta = 90^{\circ}$). To account for absorption the crystal shape was approximated to a sphere. The structure was refined by full-matrix least squares (Finger, 1969) with scattering factors for neutral atoms (Cromer & Mann, 1968) corrected for anomalous dispersion (Cromer & Liberman, 1970). Weights were assigned according to counting statistics. The final R is 0.035 for 217 structure amplitudes greater than three standard deviations. *R* is 0.069 for all 355 *F* values, including a large number of reflections which are absent because of the special point positions of the TiSi₂ structure. These reflections, which are allowed for models with anisotropic thermal parameters, were practically all too weak to be observed under the given experimental conditions.‡

The structure of TiSi₂ has only one adjustable positional parameter. From packing considerations, this parameter was assigned by Laves & Wallbaum (1939) the ideal value (transformed to the present setting) of $x = \frac{1}{8} + \frac{1}{3} = 0.4583$, which is quite close to the value found in the present investigation (Table 1). Thus none of the interatomic

Table 1. Atomic coordinates and thermal parameters for TiSi,

Thermal parameters $(\times 10^4)$ are of the form $\exp(-\sum \sum h_i h_j b_{ij})$. Equivalent isotropic *B* values (Å²) are also given.

	Ti	Si
Space group Fddd*	8(<i>a</i>)	16(<i>e</i>)
х	18	0.4615 ± 0.000
.у.	18	*
Z	1 8	18
D ₁₁	9 ± 1	21 ± 1
D ₂₂	26 ± 2	54 ± 3
$b_{33} = b$	6 <u>+</u> 1	12 ± 1
$b_{12} = b_{13}$	0	0
B	0.23	7 ± 2 0.48
	·	0.40

* Setting with origin at center of symmetry.

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[‡] A list of structure factors has been deposited with the British Library Lending Division as Supplementary Publication No. SUP 32537 (3 pp.). Copies may be obtained through The Executive Secretary, International Union of Crystallography, 13 White Friars, Chester CH1 1NZ, England.

Table 2. Interatomic distances (Å) in TiSi₂

All distances shorter than 3.8 Å are given. Standard deviations are all less than 0.001 Å.

Ti–4Si	2.554	Si-2Ti	2.554
4Si	2.754	2Ti	2.754
2Si	2.782	1 T i	2.782
4Ti	3.206	2Si	2.533
		1 Si	2.703
		2Si	2.794
		4Si	3.206

distances (Table 2) differ by more than 0.05 Å from the values of the original determination (multiplied by 1.002 to convert to the presently accepted Å unit), and most agree much better than that.

Bonding in compounds with $TiSi_2$ -, $CrSi_2$ -, and $MoSi_2$ -type structures is not well understood. Both the transition-metal and the Si atoms have large coordination numbers of 10 or 14, depending on whether atoms at about 3.2 Å are counted as neighbors. Also the shortest Si–Si distances are considerably greater than the single-bond distance of 2.35 Å. Thus two-electron bonds, a dominant feature of many transition-metal diphosphides (Jeitschko & Donohue, 1973), can certainly be excluded in these disilicides.

While $CrSi_2$ is semiconducting (Nishida, 1972, and references therein), VSi_2 (with the $CrSi_2$ -type structure) and TiSi_2 have metallic conductivity (Robins, 1958). The relative arrangement of the near-neighbors up to 4 Å is the same for the $CrSi_2$ - and $TiSi_2$ -type structures (for instance for an atom in a layer *B* the near-neighbors are the same in stacking sequences *ABC* and *ABCD*). Exact interatomic distances for $CrSi_2$ are not known. The structure was determined from powder data (Borén, 1933) and the only adjustable parameter was obtained from packing considerations. However, the structure of NbSi₂ (CrSi₂ type) was recently refined (Kubiak, Horyń, Broda & Łukaszewicz, 1972). In this structure all near-neighbor distances agree well with the corresponding ones in TiSi₂.

The great similarity of near-neighbor environments in the TiSi,- and CrSi,-type compounds suggests similar band structures. Since CrSi, is semiconducting, it has no partially filled bands, i.e. 14 valence electrons per formula unit are needed for band filling. In the metallic conductors TiSi, and VSi₂, with 12 and 13 valence electrons per formula unit, the top band apparently is only partially filled. On the other hand, the TiSi, type compounds RuAl₂ (Schwomma, Nowotny & Wittmann, 1963) and RuGa₂ (Jeitschko, Holleck, Nowotny & Benesovsky, 1963) should be semiconductors or semimetals, since they, like CrSi₂, have 14 valence electrons per formula unit. Recent results (Chen, 1975) show that RuAl, is indeed semiconducting. Thus a rigid band model seems to account well for the conducting properties of the closely related TiSi,- and CrSi,-type compounds.

In the defect-TiSi, related structures, also called Nowotny chimney ladder structures (Pearson, 1970), the composition is controlled by valence-electron concentrations in such a way that the number of valence electrons per transition-metal site (i.e. TiSi,-like subcell) practically never exceeds the 'magic' number 14 (Jeitschko & Parthé, 1967); the same number is associated with semiconductivity in CrSi, and RuAl₂. This suggests that the band structures of the Nowotny chimney ladder structures are similar to those of the TiSi,- and CrSi,-type compounds, and that additional valence electrons per T site would need to be accommodated in destabilizing bands. Since the building principle of these phases allows for a variation of the composition, the most stable composition is adjusted in such a way that no valence electrons have to be accommodated in these destabilizing (antibonding) bonds. The exact level ordering of the band structure remains of course to be determined.

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